查询SN7423供应商

捷多邦,专业PCB打样工厂,24小时加急出货

SN5423, SN5425, SN7423, SN7425 DUAL 4-INPUT NOR GATES WITH STROBE

SDLS082

DECEMBER 1983-REVISED MARCH 1988

- Package Options Include Plastic and Ceramic DIPs and Ceramic Flat Packages
- Dependable Texas Instruments Quality and Reliability

description

These devices contain dual 4-input positive NOR gates with strobe. They perform the Boolean function;

 $Y = \overline{G(A + B + C + D)}$ (with 1X and 1X of '23 left open).

The SN5423 and the SN5425 are characterized for operation over the full military temperature range of -55 °C to 125 °C. The SN7423 and the SN7425 are characterized for operation from 0 °C to 70 °C.

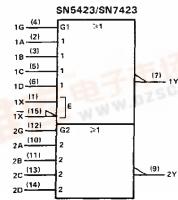
1

FUN	CTION	TABLE

	IP	OUTPUT			
А	в	С	D	G	Y
н	х	х	х	н	L
х	н	х	х	н	L
х	х	н	х	н	L
x	×	х	н	н	L [
L	L	L	L	х	н
×	х	х	х	L	н

Expander inputs are open, H = high level, L = low level, X = irrelevant

logic symbols[†]



[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pinnumbers are for J, N, or W packages.

PRODUCTION DATA documents contain information current as of publication date. Products conform to Specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include texting of all nearampters

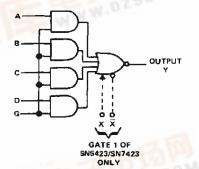


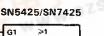
	J OR W PACKAGE							
(TOP VIEW)								
1X [[ī	U16∐ V <u>c</u> c							
1A [2	15 🗌 1X							
1 B [3	14 🗍 2D							
1G [4	13 🗌 2C							
1C 🗍 5	12 🛛 2G							
1D 🚺 6	11 🗋 2B							
1Y 🚺 7	10 2A							
GND 🗍 8	<u>9</u>] 2Y							

SN5425 ... J OR W PACKAGE SN7425 ... N PACKAGE (TOP VIEW) 1A 1 1 14 VCC

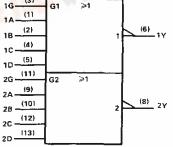
1A 🗌	1	
1 B 🗋	2	13 2D
1G 🗖	3	12 2C
10 🗋	4	11 2G
1D 🗋	5	10 2B
1Y 🗋	6	9 🗋 2 A
	7	8 2 Y

logic diagram



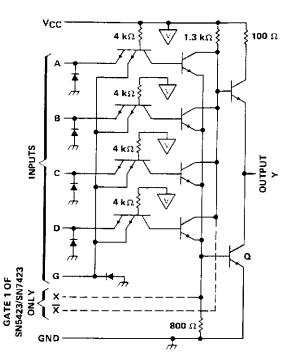


(3)



SN5423, SN5425, SN7423, SNSN7425 DUAL 4-INPUT NOR GATES WITH STROBE

schematic (each gate)



NOTES: A. Component values shown are nominal.

B. Both expander inputs are used simultaneously for expanding.

- C. If expander is not used leave X and X open.
- D. A total of four expander gates can be connected to the expander inputs.
- ∇ V_{CC} bus

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage V _{CC} (see Note 1)	
Input voltage (see Note 1)	5.5 V
Interemitter voltage (see Note 2)	
Operating free-air temperature range: SN5423, SN5425 Circuits	. – 55°C to 125°C
SN7423, SN7425 Circuits	0°C to 70°C
Storage temperature range	. – 65°C to 150°C

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal. 2. This is the voltage between two emitters of a multiple-emitter transistor.

recommended operating conditions

			'23 , '25			
			MIN	NOM	MAX	UNIT
		54 Family	4.5	5	5.5	v
Vcc	CC Supply voltage	74 Family	4.75	5	5.25	
⊻ін	High-level input voltage		2			v
VIL	Low-level input voltage				0.8	V
юн	High-level output current				- 0.8	mA
1		54 Family			16	mА
IOL	Low-level output current	74 Family			16	
		54 Familγ	- 55		125	°c
TA	Operating free-air temperature range	74 Family	0		70	

The '23 is designed for use with up to four '60 expanders.



SN5423, SN5425, SN7423, SN7425 DUAL 4-INPUT NOR GATES WITH STROBE

TYP[‡] MAX UNIT TEST CONDITIONS[†] MIN PARAMETER $\overline{\nu}_{\rm F}$ - 1.5 v VCC = MIN, I_I = - 12 mA Vcc = MIN, V_{IL} = 0.8 V, 2.4 3.4 V I_{OH} = - 0.8 mA ⊻он IOL = 16 mA V_{CC} = MIN, 0.2 0.4 V V_{1H} = 2 V, Vol VI = 5.5 V 1 mΑ V_{CC} = MAX, Ιį. 40 data inputs VCC = MAX, V₁ = 2.4 V μA ЧН 160 strobe inputs -- 1.6 data inputs $V_{CC} = MAX$, V₁ = 0.4 V mΑ **IL** - 6.4 strobe inputs 54 Family - 20 - 55 V_{CC} = MAX mΑ loss - 18 - 55 74 Family V_{CC} = MAX, All inputs at 0 V 8 16 mΑ 1ССН V_{CC} = MAX, All inputs at 5 V 10 19 mΑ ICCL

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

T For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander inputs X and \overline{X} are open.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

2

§ Not more than one output should be shorted at a time.

electrical characteristics (SN5423 circuits) using expander inputs, VCC = 4.5 V, TA = -55°C

	PARAMETER	TEST CONDITIONS			MIN T	TYP [†]	MAX	UNIT
<u>کا</u>	Expander current	V _X x = 0.4 V,	loL = 16 mA				- 3.5	mА
VBE(Q)	Base-Emitter voltage of output transistor (Q)	I _{OL} = 16 mA,	Ix + Ix = 0.41 mA,	$R_{X}\overline{X} = 0$			1 .1	v
Voн	High-level output voltage	1 _{ОН} = - 0.4 mA,	Ix = 0.15 mA,	l <u>⊼</u> = 0.15 mA	2.4	3.4		v
VOL	Low-level output voltage	I _{OL} = 16 mA,	lχ + lχ = 0.3 mA,	R _X x z = 114 Ω		0.2	0.4	V

electrical characteristics (SN7423 circuits) using expander inputs, V_{CC} = 4.75 V, T_A = 0° C

PARAMETER		RAMETER TEST CONDITIONS			MIN	түрт	MAX	UNIT
1 <u>x</u>	Expander current	Vxx = 0.4 ∨,	1 _{0L} = 16 mA				- 3.8	mΑ
VBE(Q)	Base-Emitter voltage of output transistor (Q)	I _{OL} = 16 mA,	Iχ + I <u>⊼</u> ≈ 0.62 mA,	R _X X = 0			1	v
√он	High-level output voltage	lOH = - 0.4 mA,	I _X = 0.27 mA,	1 χ = 0.27 mA	2.4	3.4		V
VOL	Low-level output voltage	IOL= 16 mA,	$1\chi + 1\chi = 0.43 \text{ mA},$	Ħχズ = 130 Ω		0.2	0.4	V

† All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

switching characteristics, VCC = 5 V, TA = 25°C, N = 10, (see note 3)

PARAMETER	TEST CONDITIONS			MAX	UNIT
TPLH	RL = 400 Ω, CL = 15 pF		13	22	nş
^t PHL	R _L = 400 Ω, C _L = 15 ρF		8	15	ns

NOTE 3: Switching characteristics of the SN5423 and SN7424 are tested with the expander pins open.



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated